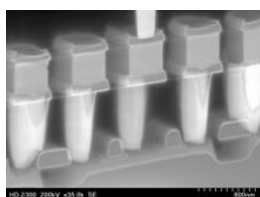
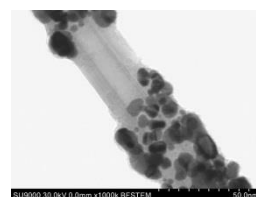




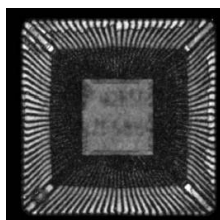
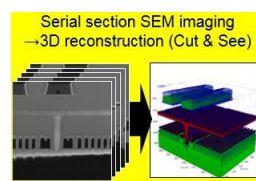
SOLUTIONS DE CARACTERISATION PHYSIQUE ET ELECTRIQUE



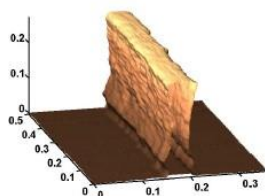
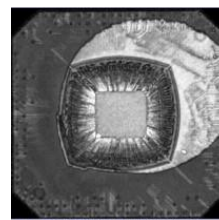
**Microscopes
électroniques
(MEB, MET)**



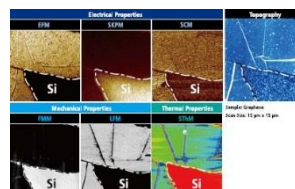
FIB



**Microscopes
Acoustiques
(SAT)**



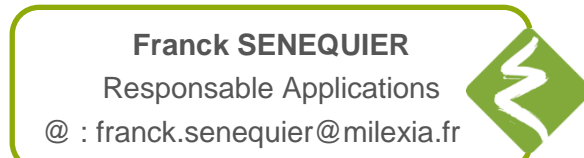
**Microscopes
en champ
proche (AFM)**



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